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Sheet 1 of 1

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Attorney Docket No.: L&L-I0217 Appl. No.: 10/620,093
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant: JÖRG BERTHOLD ET AL.
		Filing Date: July 15, 2003 Group Art Unit: 2825

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
A							
B							
C							
D							
E							
F							
G							
H							
I							

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
PJ	J	199 00 974 A1	9/16/99	Germany	601R	31/3183	Abstract
PJ	K	0 259 705 B1	3/16/88	Europe	606 F	15/60	✓
PJ	L	93/18468	9/16/93	WIPO	606 F	15/60	✓
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
PJ	International Preliminary Examination Report for PCT/DE01/04457, pp 1-7, Bowman, K. A. et al.: "Impact of Extrinsic and Intrinsic Parameter Fluctuations on CMOS Circuit Performance", IEEE Journal of Solid-State Circuits, Vol. 35, No. 8, August 2000, pp. 1186-1193 English translation, filed 11/24/2003.
PJ	Eisele, M. et al.: "The Impact of Intra-Die Device Parameter Variations on Path Delays and on the Design for Yield of Low Voltage Digital Circuits", IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Vol. 5, No. 4, December 1997, pp. 360-368
EXAMINER	DATE CONSIDERED
Phallaka Kirk	10/19/2005